AMD Xilinx - XCS10XL-4VQG100C Datasheet

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	196
Number of Logic Elements/Cells	466
Total RAM Bits	6272
Number of I/O	77
Number of Gates	10000
Voltage - Supply	3V ~ 3.6V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs10xl-4vqg100c

Spartan and Spartan-XL devices provide system clock rates exceeding 80 MHz and internal performance in excess of 150 MHz. In addition to the conventional benefit of high volume programmable logic solutions, Spartan series FPGAs also offer on-chip edge-triggered single-port and dual-port RAM, clock enables on all flip-flops, fast carry logic, and many other features.

The Spartan/XL families leverage the highly successful XC4000 architecture with many of that family's features and benefits. Technology advancements have been derived from the XC4000XLA process developments.

Logic Functional Description

The Spartan series uses a standard FPGA structure as shown in Figure 1, page 2. The FPGA consists of an array of configurable logic blocks (CLBs) placed in a matrix of routing channels. The input and output of signals is achieved through a set of input/output blocks (IOBs) forming a ring around the CLBs and routing channels.

- CLBs provide the functional elements for implementing the user's logic.
- IOBs provide the interface between the package pins and internal signal lines.
- Routing channels provide paths to interconnect the inputs and outputs of the CLBs and IOBs.

The functionality of each circuit block is customized during configuration by programming internal static memory cells. The values stored in these memory cells determine the logic functions and interconnections implemented in the FPGA.

Configurable Logic Blocks (CLBs)

The CLBs are used to implement most of the logic in an FPGA. The principal CLB elements are shown in the simplified block diagram in Figure 2. There are three look-up tables (LUT) which are used as logic function generators, two flip-flops and two groups of signal steering multiplexers. There are also some more advanced features provided by the CLB which will be covered in the **Advanced Features Description**, page 13.

Function Generators

Two 16 x 1 memory look-up tables (F-LUT and G-LUT) are used to implement 4-input function generators, each offering unrestricted logic implementation of any Boolean function of up to four independent input signals (F1 to F4 or G1 to G4). Using memory look-up tables the propagation delay is independent of the function implemented.

A third 3-input function generator (H-LUT) can implement any Boolean function of its three inputs. Two of these inputs are controlled by programmable multiplexers (see box "A" of Figure 2). These inputs can come from the F-LUT or G-LUT outputs or from CLB inputs. The third input always comes from a CLB input. The CLB can, therefore, implement certain functions of up to nine inputs, like parity checking. The three LUTs in the CLB can also be combined to do any arbitrarily defined Boolean function of five inputs.

Output Multiplexer/2-Input Function Generator (Spartan-XL Family Only)

The output path in the Spartan-XL family IOB contains an additional multiplexer not available in the Spartan family IOB. The multiplexer can also be configured as a 2-input function generator, implementing a pass gate, AND gate, OR gate, or XOR gate, with 0, 1, or 2 inverted inputs.

When configured as a multiplexer, this feature allows two output signals to time-share the same output pad, effectively doubling the number of device outputs without requiring a larger, more expensive package. The select input is the pin used for the output flip-flop clock, OK.

When the multiplexer is configured as a 2-input function generator, logic can be implemented within the IOB itself. Combined with a Global buffer, this arrangement allows very high-speed gating of a single signal. For example, a wide decoder can be implemented in CLBs, and its output gated with a Read or Write Strobe driven by a global buffer.

The user can specify that the IOB function generator be used by placing special library symbols beginning with the letter "O." For example, a 2-input AND gate in the IOB function generator is called OAND2. Use the symbol input pin labeled "F" for the signal on the critical path. This signal is placed on the OK pin — the IOB input with the shortest delay to the function generator. Two examples are shown in Figure 7.

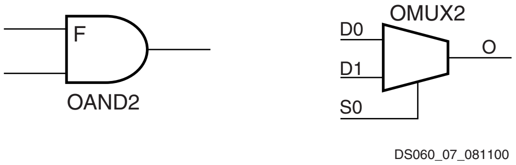


Figure 7: **AND and MUX Symbols in Spartan-XL IOB**

Output Buffer

An active High 3-state signal can be used to place the output buffer in a high-impedance state, implementing 3-state outputs or bidirectional I/O. Under configuration control, the output (O) and output 3-state (T) signals can be inverted. The polarity of these signals is independently configured for each IOB (see Figure 6, page 7). An output can be configured as open-drain (open-collector) by tying the 3-state pin (T) to the output signal, and the input pin (I) to Ground.

By default, a 5V Spartan device output buffer pull-up structure is configured as a TTL-like totem-pole. The High driver is an n-channel pull-up transistor, pulling to a voltage one transistor threshold below V_{CC}. Alternatively, the outputs can be globally configured as CMOS drivers, with additional p-channel pull-up transistors pulling to V_{CC}. This option, applied using the bitstream generation software, applies to all outputs on the device. It is not individually programmable.

All Spartan-XL device outputs are configured as CMOS drivers, therefore driving rail-to-rail. The Spartan-XL family outputs are individually programmable for 12 mA or 24 mA output drive.

Any 5V Spartan device with its outputs configured in TTL mode can drive the inputs of any typical 3.3V device. Supported destinations for Spartan/XL device outputs are shown in Table 7.

Three-State Register (Spartan-XL Family Only)

Spartan-XL devices incorporate an optional register controlling the three-state enable in the IOBs. The use of the three-state control register can significantly improve output enable and disable time.

Output Slew Rate

The slew rate of each output buffer is, by default, reduced, to minimize power bus transients when switching non-critical signals. For critical signals, attach a FAST attribute or property to the output buffer or flip-flop.

Spartan/XL devices have a feature called "Soft Start-up," designed to reduce ground bounce when all outputs are turned on simultaneously at the end of configuration. When the configuration process is finished and the device starts up, the first activation of the outputs is automatically slew-rate limited. Immediately following the initial activation of the I/O, the slew rate of the individual outputs is determined by the individual configuration option for each IOB.

Pull-up and Pull-down Network

Programmable pull-up and pull-down resistors are used for tying unused pins to V_{CC} or Ground to minimize power consumption and reduce noise sensitivity. The configurable pull-up resistor is a p-channel transistor that pulls to V_{CC}. The configurable pull-down resistor is an n-channel transistor that pulls to Ground. The value of these resistors is typically 20 KΩ – 100 KΩ (See "Spartan Family DC Characteristics Over Operating Conditions" on page 43.).

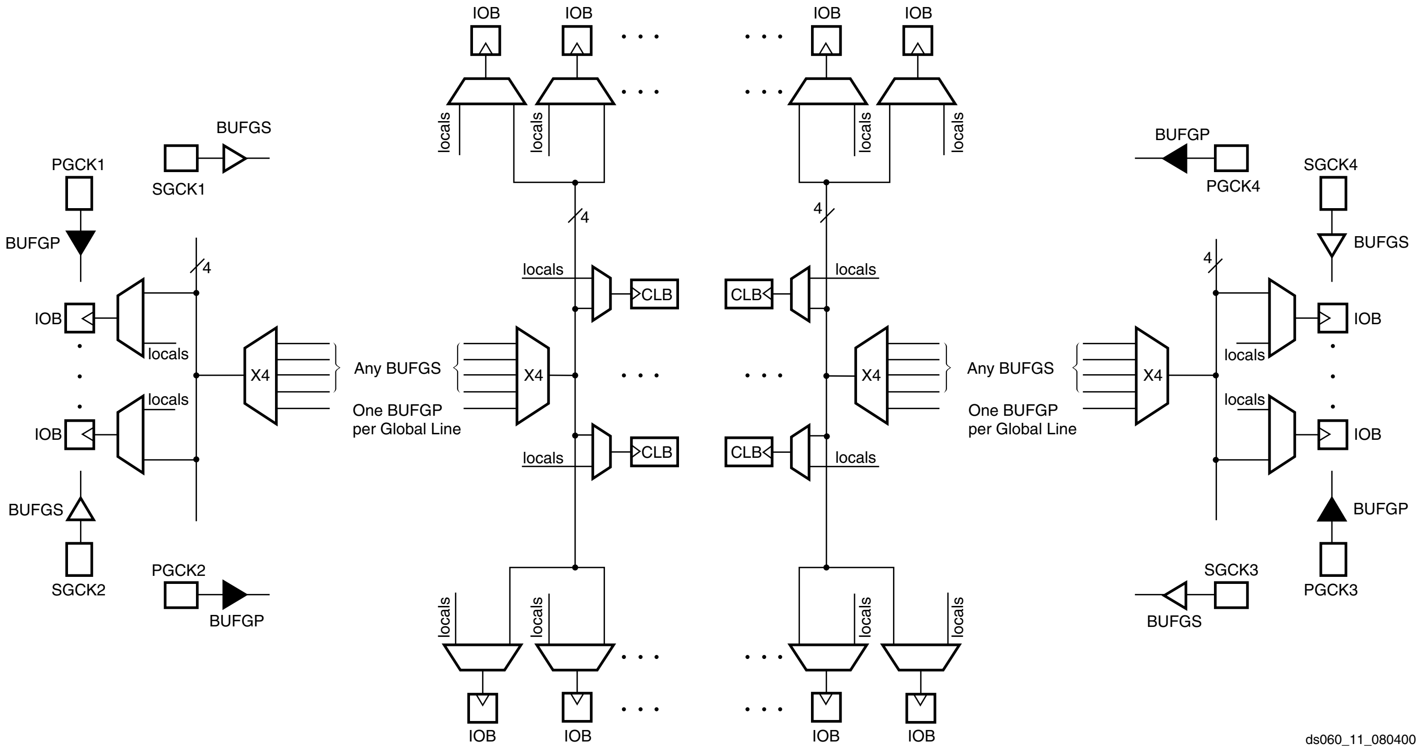


Figure 11: **5V Spartan Family Global Net Distribution**

The four Primary Global buffers offer the shortest delay and negligible skew. Four Secondary Global buffers have slightly longer delay and slightly more skew due to potentially heavier loading, but offer greater flexibility when used to drive non-clock CLB inputs. The eight Global Low-Skew buffers in the Spartan-XL devices combine short delay, negligible skew, and flexibility.

The Primary Global buffers must be driven by the semi-dedicated pads (PGCK1-4). The Secondary Global buffers can be sourced by either semi-dedicated pads (SGCK1-4) or internal nets. Each corner of the device has one Primary buffer and one Secondary buffer. The Spartan-XL family has eight global low-skew buffers, two in each corner. All can be sourced by either semi-dedicated pads (GCK1-8) or internal nets.

Using the library symbol called BUFG results in the software choosing the appropriate clock buffer, based on the timing requirements of the design. A global buffer should be specified for all timing-sensitive global signal distribution. To use a global buffer, place a BUFGP (primary buffer), BUFGS (secondary buffer), BUFGLS (Spartan-XL family global low-skew buffer), or BUFG (any buffer type) element in a schematic or in HDL code.

Advanced Features Description

Distributed RAM

Optional modes for each CLB allow the function generators (F-LUT and G-LUT) to be used as Random Access Memory (RAM).

Read and write operations are significantly faster for this on-chip RAM than for off-chip implementations. This speed advantage is due to the relatively short signal propagation delays within the FPGA.

Memory Configuration Overview

There are two available memory configuration modes: single-port RAM and dual-port RAM. For both these modes, write operations are synchronous (edge-triggered), while read operations are asynchronous. In the single-port mode, a single CLB can be configured as either a 16 x 1, (16 x 1) x 2, or 32 x 1 RAM array. In the dual-port mode, a single CLB can be configured only as one 16 x 1 RAM array. The different CLB memory configurations are summarized in Table 8. Any of these possibilities can be individually programmed into a Spartan/XL FPGA CLB.

Table 8: **CLB Memory Configurations**

Mode	16 x 1	(16 x 1) x 2	32 x 1
Single-Port	√	√	√
Dual-Port	√	–	–

Figure 20 is a diagram of the Spartan/XL FPGA boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

Spartan/XL devices can also be configured through the boundary scan logic. See **Configuration Through the Boundary Scan Pins**, page 37.

Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out and 3-state Control. Non-IOB pins have appropriate partial bit population for In or Out only. $\overline{\text{PROGRAM}}$, CCLK and DONE are not included in the boundary scan register. Each EXTEST CAPTURE-DR state captures all In, Out, and 3-state pins.

The data register also includes the following non-pin bits: TDO.T, and TDO.O, which are always bits 0 and 1 of the data register, respectively, and BSCANT.UPD, which is always the last bit of the data register. These three boundary scan bits are special-purpose Xilinx test signals.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA provides two additional data registers that can be specified using the BSCAN macro. The FPGA provides two user pins (BSCAN.SEL1 and BSCAN.SEL2) which are the decodes of two user instructions. For these instructions, two corresponding pins (BSCAN.TDO1 and BSCAN.TDO2) allow user scan data to be shifted out on TDO. The data register clock (BSCAN.DRCK) is available for control of test logic which the user may wish to implement with CLBs. The NAND of TCK and RUN-TEST-IDLE is also provided (BSCAN.IDLE).

Instruction Set

The Spartan/XL FPGA boundary scan instruction set also includes instructions to configure the device and read back the configuration data. The instruction set is coded as shown in Table 12.

Table 12: **Boundary Scan Instructions**

Instruction			Test Selected	TDO Source	I/O Data Source
I2	I1	I0			
0	0	0	EXTEST	DR	DR
0	0	1	SAMPLE/ PRELOAD	DR	Pin/Logic
0	1	0	USER 1	BSCAN. TDO1	User Logic
0	1	1	USER 2	BSCAN. TDO2	User Logic
1	0	0	READBACK	Readback Data	Pin/Logic
1	0	1	CONFIGURE	DOUT	Disabled
1	1	0	IDCODE (Spartan-XL only)	IDCODE Register	-
1	1	1	BYPASS	Bypass Register	-

Bit Sequence

The bit sequence within each IOB is: In, Out, 3-state. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contributes all three bits.

The first two bits in the I/O data register are TDO.T and TDO.O, which can be used for the capture of internal signals. The final bit is BSCANT.UPD, which can be used to drive an internal net. These locations are primarily used by Xilinx for internal testing.

From a cavity-up view of the chip (as shown in the FPGA Editor), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in Figure 21. The device-specific pinout tables for the Spartan/XL devices include the boundary scan locations for each IOB pin.

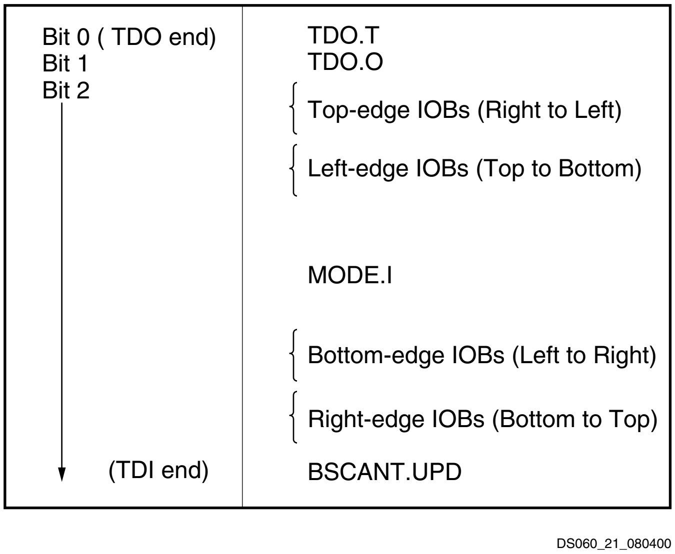


Figure 21: **Boundary Scan Bit Sequence**

BSDL (Boundary Scan Description Language) files for Spartan/XL devices are available on the Xilinx website in the File Download area. Note that the 5V Spartan devices and 3V Spartan-XL devices have different BSDL files.

Including Boundary Scan in a Design

If boundary scan is only to be used during configuration, no special elements need be included in the schematic or HDL code. In this case, the special boundary scan pins TDI, TMS, TCK and TDO can be used for user functions after configuration.

To indicate that boundary scan remain enabled after configuration, place the BSCAN library symbol and connect the TDI, TMS, TCK and TDO pad symbols to the appropriate pins, as shown in Figure 22.

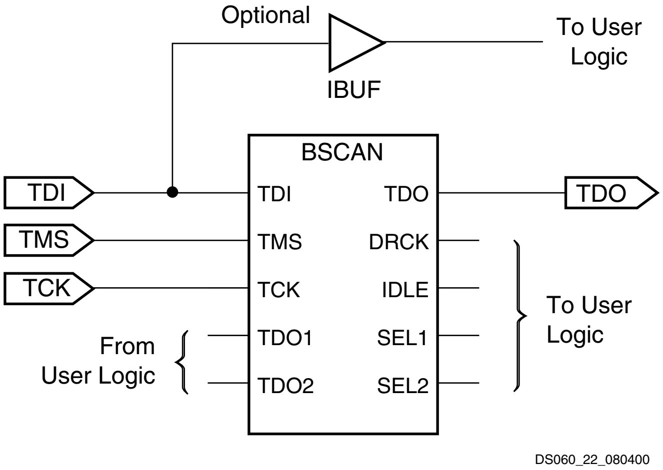


Figure 22: **Boundary Scan Example**

Master Serial Mode

The Master serial mode uses an internal oscillator to generate a Configuration Clock (CCLK) for driving potential slave devices and the Xilinx serial-configuration PROM (SPROM). The CCLK speed is selectable as either 1 MHz (default) or 8 MHz. Configuration always starts at the default slow frequency, then can switch to the higher frequency during the first frame. Frequency tolerance is –50% to +25%.

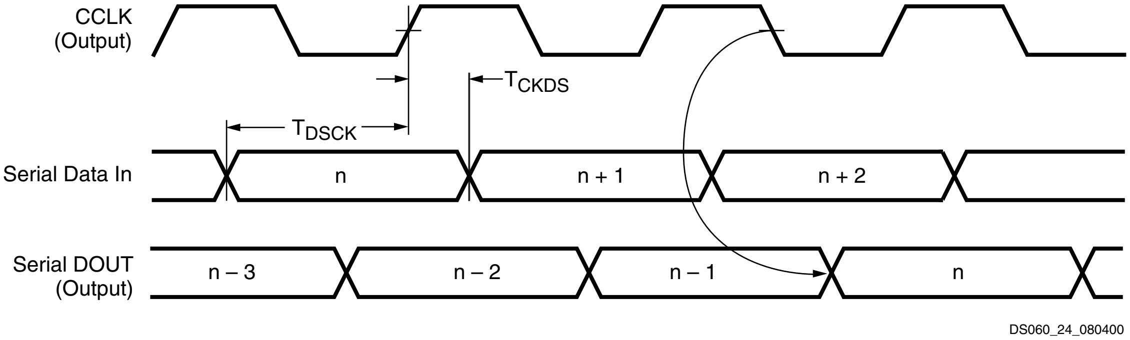
In Master Serial mode, the CCLK output of the device drives a Xilinx SPROM that feeds the FPGA DIN input. Each rising edge of the CCLK output increments the Serial PROM internal address counter. The next data bit is put on the SPROM data output, connected to the FPGA DIN pin. The FPGA accepts this data on the subsequent rising CCLK edge.

When used in a daisy-chain configuration the Master Serial FPGA is placed as the first device in the chain and is referred to as the lead FPGA. The lead FPGA presents the preamble data, and all data that overflows the lead device, on its DOUT pin. There is an internal pipeline delay of 1.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge. See the timing diagram in Figure 24.

In the bitstream generation software, the user can specify Fast Configuration Rate, which, starting several bits into the first frame, increases the CCLK frequency by a factor of eight. For actual timing values please refer to the specification section. Be sure that the serial PROM and slaves are fast enough to support this data rate. Earlier families such as the XC3000 series do not support the Fast Configuration Rate option.

The SPROM $\overline{\text{CE}}$ input can be driven from either $\overline{\text{LDC}}$ or DONE. Using $\overline{\text{LDC}}$ avoids potential contention on the DIN pin, if this pin is configured as user I/O, but $\overline{\text{LDC}}$ is then restricted to be a permanently High user output after configuration. Using DONE can also avoid contention on DIN, provided the Early DONE option is invoked.

Figure 25 shows a full master/slave system. The leftmost device is in Master Serial mode, all other devices in the chain are in Slave Serial mode.



	Symbol	Description	Min	Units
CCLK	T_{DSCK}	DIN setup	20	ns
	T_{CKDS}	DIN hold	0	ns

Notes:
1. At power-up, V_{CC} must rise from 2.0V to V_{CC} min in less than 25 ms, otherwise delay configuration by pulling $\overline{\text{PROGRAM}}$ Low until V_{CC} is valid.
2. Master Serial mode timing is based on testing in slave mode.

Figure 24: **Master Serial Mode Programming Switching Characteristics**

Slave Serial Mode

In Slave Serial mode, the FPGA receives serial configuration data on the rising edge of CCLK and, after loading its configuration, passes additional data out, resynchronized on the next falling edge of CCLK.

In this mode, an external signal drives the CCLK input of the FPGA (most often from a Master Serial device). The serial configuration bitstream must be available at the DIN input of the lead FPGA a short setup time before each rising CCLK edge.

The lead FPGA then presents the preamble data—and all data that overflows the lead device—on its DOUT pin. There is an internal delay of 0.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

Figure 25 shows a full master/slave system. A Spartan/XL device in Slave Serial mode should be connected as shown in the third device from the left.

Slave Serial is the default mode if the Mode pins are left unconnected, as they have weak pull-up resistors during configuration.

Multiple slave devices with identical configurations can be wired with parallel DIN inputs. In this way, multiple devices can be configured simultaneously.

Serial Daisy Chain

Multiple devices with different configurations can be connected together in a "daisy chain," and a single combined bitstream used to configure the chain of slave devices.

To configure a daisy chain of devices, wire the CCLK pins of all devices in parallel, as shown in Figure 25. Connect the DOUT of each device to the DIN of the next. The lead or master FPGA and following slaves each passes resynchronized configuration data coming from a single source. The header data, including the length count, is passed through and is captured by each FPGA when it recognizes the 0010 preamble. Following the length-count data, each FPGA outputs a High on DOUT until it has received its required number of data frames.

After an FPGA has received its configuration data, it passes on any additional frame start bits and configuration data on DOUT. When the total number of configuration clocks applied after memory initialization equals the value of the 24-bit length count, the FPGAs begin the start-up sequence and become operational together. FPGA I/O are normally released two CCLK cycles after the last configuration bit is received.

The daisy-chained bitstream is not simply a concatenation of the individual bitstreams. The PROM File Formatter must be used to combine the bitstreams for a daisy-chained configuration.

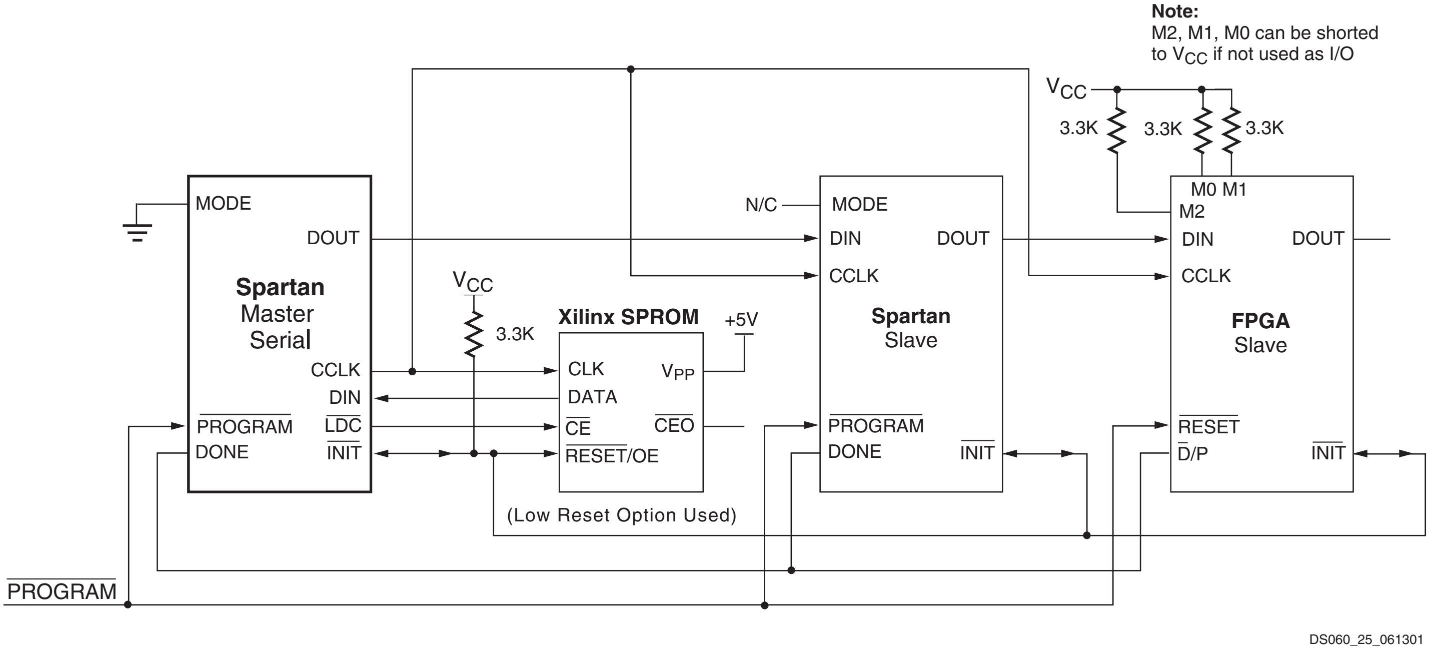
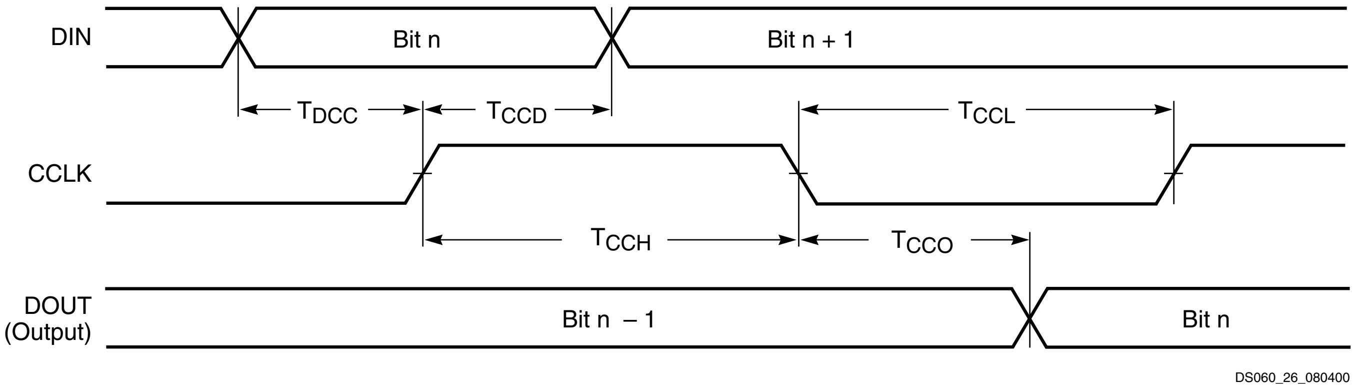

Note:
M2, M1, M0 can be shorted to V_{CC} if not used as I/O

Figure 25: **Master/Slave Serial Mode Circuit Diagram**



Symbol		Description	Min	Max	Units
T_{DCC}	CCLK	DIN setup	20	-	ns
T_{CCD}		DIN hold	0	-	ns
T_{CCO}		DIN to DOUT	-	30	ns
T_{CCH}		High time	40	-	ns
T_{CCL}		Low time	40	-	ns
F_{CC}		Frequency	-	12.5	MHz

Notes:

1. Configuration must be delayed until the $\overline{\text{INIT}}$ pins of all daisy-chained FPGAs are High.

Figure 26: **Slave Serial Mode Programming Switching Characteristics**

Express Mode (Spartan-XL Family Only)

Express mode is similar to Slave Serial mode, except that data is processed one byte per CCLK cycle instead of one bit per CCLK cycle. An external source is used to drive CCLK, while byte-wide data is loaded directly into the configuration data shift registers (Figure 27). A CCLK frequency of 1 MHz is equivalent to a 8 MHz serial rate, because eight bits of configuration data are loaded per CCLK cycle. Express mode does not support CRC error checking, but does support constant-field error checking. A length count is not used in Express mode.

Express mode must be specified as an option to the development system. The Express mode bitstream is not compatible with the other configuration modes (see Table 16, page 32.) Express mode is selected by a <0X> on the Mode pins (M1, M0).

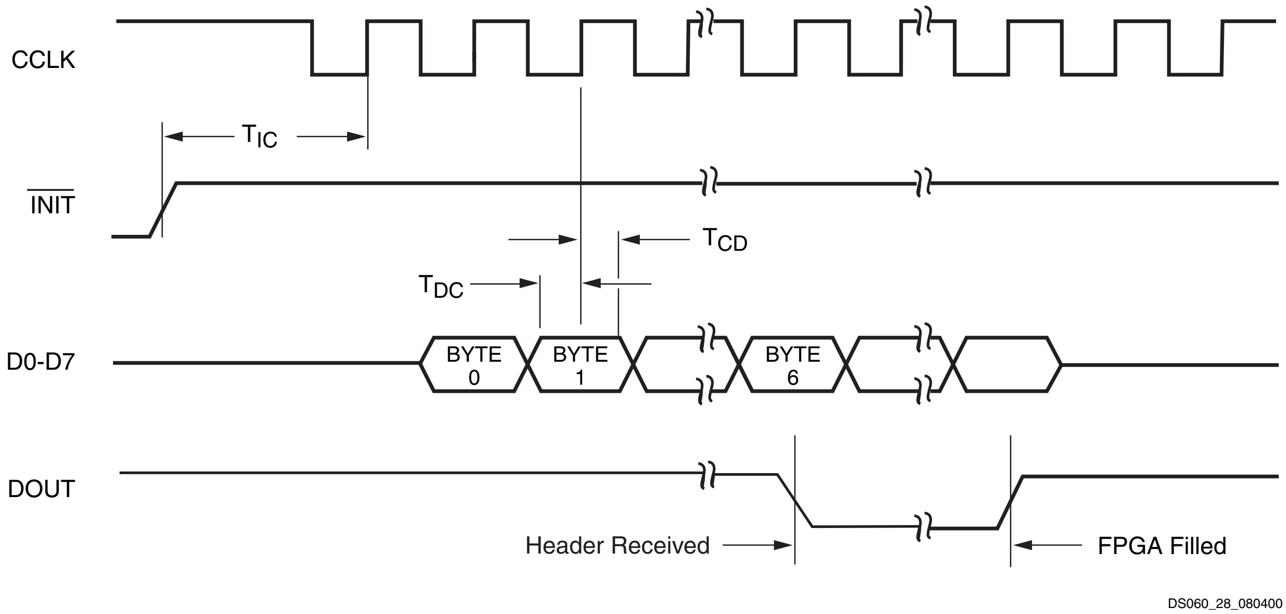
The first byte of parallel configuration data must be available at the D inputs of the FPGA a short setup time before the second rising CCLK edge. Subsequent data bytes are clocked in on each consecutive rising CCLK edge (Figure 28).

Pseudo Daisy Chain

Multiple devices with different configurations can be configured in a pseudo daisy chain provided that all of the devices are in Express mode. Concatenated bitstreams are used to configure the chain of Express mode devices so that each device receives a separate header. CCLK pins are tied together and D0-D7 pins are tied together for all devices along the chain. A status signal is passed from DOUT to CS1 of successive devices along the chain. Frame data is accepted only when CS1 is High and the device's configuration memory is not already full. The lead device in the chain has its CS1 input tied High (or floating, since there is an internal pull-up). The status pin DOUT is pulled Low after the header is received, and remains Low until the device's configuration memory is full. DOUT is then pulled High to signal the next device in the chain to accept the next header and configuration data on the D0-D7 bus.

The DONE pins of all devices in the chain should be tied together, with one or more active internal pull-ups. If a large number of devices are included in the chain, deactivate some of the internal pull-ups, since the Low-driving DONE pin of the last device in the chain must sink the current from all pull-ups in the chain. The DONE pull-up is activated by default. It can be deactivated using a development system option.

The requirement that all DONE pins in a daisy chain be wired together applies only to Express mode, and only if all devices in the chain are to become active simultaneously. All Spartan-XL devices in Express mode are synchronized



Symbol		Description	Min	Max	Units
T_{IC}	CCLK	$\overline{\text{INIT}}$ (High) setup time	5	-	µs
T_{DC}		D0-D7 setup time	20	-	ns
T_{CD}		D0-D7 hold time	0	-	ns
T_{CCH}		CCLK High time	45	-	ns
T_{CCL}		CCLK Low time	45	-	ns
F_{CC}		CCLK Frequency	-	10	MHz

Notes:

1. If not driven by the preceding DOUT, CS1 *must* remain High until the device is fully configured.

Figure 28: **Express Mode Programming Switching Characteristics**

Setting CCLK Frequency

In Master mode, CCLK can be generated in either of two frequencies. In the default slow mode, the frequency ranges from 0.5 MHz to 1.25 MHz for Spartan/XL devices. In fast CCLK mode, the frequency ranges from 4 MHz to 10 MHz for Spartan/XL devices. The frequency is changed to fast by an option when running the bitstream generation software.

Data Stream Format

The data stream ("bitstream") format is identical for both serial configuration modes, but different for the Spartan-XL family Express mode. In Express mode, the device becomes active when DONE goes High, therefore no length count is required. Additionally, CRC error checking is not supported in Express mode. The data stream format is shown in Table 16. Bit-serial data is read from left to right. Express mode data is shown with D0 at the left and D7 at the right.

The configuration data stream begins with a string of eight ones, a preamble code, followed by a 24-bit length count and a separator field of ones (or 24 fill bits, in Spartan-XL family Express mode). This header is followed by the actual configuration data in frames. The length and number of frames depends on the device type (see Table 17). Each frame begins with a start field and ends with an error check. In serial modes, a postamble code is required to signal the end of data for a single device. In all cases, additional start-up bytes of data are required to provide four clocks for the startup sequence at the end of configuration. Long daisy chains require additional startup bytes to shift the last data through the chain. All start-up bytes are "don't cares".

Table 16: **Spartan/XL Data Stream Formats**

Data Type	Serial Modes (D0...)	Express Mode (D0-D7) (Spartan-XL only)
Fill Byte	11111111b	FFFFh
Preamble Code	0010b	11110010b
Length Count	COUNT[23:0]	COUNT[23:0][1]
Fill Bits	1111b	-
Field Check Code	-	11010010b
Start Field	0b	11111110b[2]
Data Frame	DATA[n–1:0]	DATA[n–1:0]
CRC or Constant Field Check	xxxx (CRC) or 0110b	11010010b
Extend Write Cycle	-	FFD2FFFFFFh
Postamble	01111111b	-
Start-Up Bytes[3]	FFh	FFFFFFFFFFFFFFh

Legend:

Unshaded	Once per bitstream
Light	Once per data frame
Dark	Once per device

Notes:

1. Not used by configuration logic.
2. 11111111b for XCS40XL only.
3. Development system may add more start-up bytes.

A selection of CRC or non-CRC error checking is allowed by the bitstream generation software. The Spartan-XL family Express mode only supports non-CRC error checking. The non-CRC error checking tests for a designated end-of-frame field for each frame. For CRC error checking, the software calculates a running CRC and inserts a unique four-bit partial check at the end of each frame. The 11-bit CRC check of the last frame of an FPGA includes the last seven data bits.

Detection of an error results in the suspension of data loading before DONE goes High, and the pulling down of the $\overline{\text{INIT}}$ pin. In Master serial mode, CCLK continues to operate externally. The user must detect $\overline{\text{INIT}}$ and initialize a new configuration by pulsing the $\overline{\text{PROGRAM}}$ pin Low or cycling V_{CC}.

Cyclic Redundancy Check (CRC) for Configuration and Readback

The Cyclic Redundancy Check is a method of error detection in data transmission applications. Generally, the transmitting system performs a calculation on the serial bitstream. The result of this calculation is tagged onto the data stream as additional check bits. The receiving system performs an identical calculation on the bitstream and compares the result with the received checksum.

Each data frame of the configuration bitstream has four error bits at the end, as shown in Table 16. If a frame data error is detected during the loading of the FPGA, the configuration process with a potentially corrupted bitstream is terminated. The FPGA pulls the $\overline{\text{INIT}}$ pin Low and goes into a Wait state.

Readback

The user can read back the content of configuration memory and the level of certain internal nodes without interfering with the normal operation of the device.

Readback not only reports the downloaded configuration bits, but can also include the present state of the device, represented by the content of all flip-flops and latches in CLBs and IOBs, as well as the content of function generators used as RAMs.

Although readback can be performed while the device is operating, for best results and to freeze a known capture state, it is recommended that the clock inputs be stopped until readback is complete.

Readback of Spartan-XL family Express mode bitstreams results in data that does not resemble the original bitstream, because the bitstream format differs from other modes.

Spartan/XL FPGA Readback does not use any dedicated pins, but uses four internal nets (RDBK.TRIG, RDBK.DATA, RDBK.RIP and RDBK.CLK) that can be routed to any IOB. To access the internal Readback signals, instantiate the READBACK library symbol and attach the appropriate pad symbols, as shown in Figure 32.

After Readback has been initiated by a Low-to-High transition on RDBK.TRIG, the RDBK.RIP (Read In Progress) output goes High on the next rising edge of RDBK.CLK. Subsequent rising edges of this clock shift out Readback data on the RDBK.DATA net.

Readback data does not include the preamble, but starts with five dummy bits (all High) followed by the Start bit (Low) of the first frame. The first two data bits of the first frame are always High.

Each frame ends with four error check bits. They are read back as High. The last seven bits of the last frame are also read back as High. An additional Start bit (Low) and an 11-bit Cyclic Redundancy Check (CRC) signature follow, before RDBK.RIP returns Low.

Readback Options

Readback options are: Readback Capture, Readback Abort, and Clock Select. They are set with the bitstream generation software.

Readback Capture

When the Readback Capture option is selected, the data stream includes sampled values of CLB and IOB signals. The rising edge of RDBK.TRIG latches the inverted values of the four CLB outputs, the IOB output flip-flops and the input signals I1 and I2. Note that while the bits describing configuration (interconnect, function generators, and RAM content) are *not* inverted, the CLB and IOB output signals *are* inverted. RDBK.TRIG is located in the lower-left corner of the device.

When the Readback Capture option is not selected, the values of the capture bits reflect the configuration data originally written to those memory locations. If the RAM capability of the CLBs is used, RAM data are available in Readback, since they directly overwrite the F and G function-table configuration of the CLB.

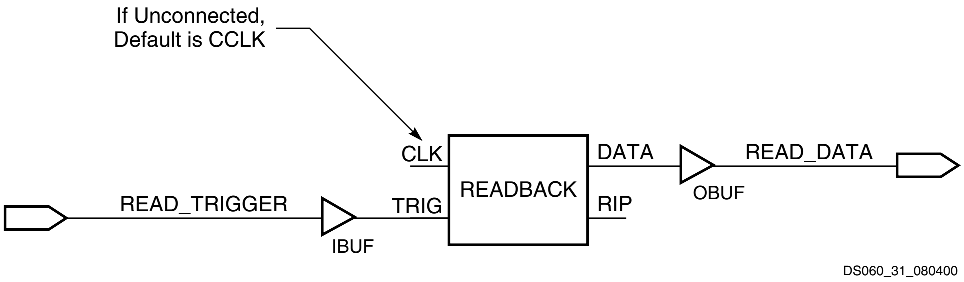


Figure 32: **Readback Example**

Spartan Family DC Characteristics Over Operating Conditions

Symbol	Description		Min	Max	Units
V_{OH}	High-level output voltage @ $I_{OH} = -4.0$ mA, V_{CC} min	TTL outputs	2.4	-	V
	High-level output voltage @ $I_{OH} = -1.0$ mA, V_{CC} min	CMOS outputs	$V_{CC} - 0.5$	-	V
V_{OL}	Low-level output voltage @ I_{OL} = 12.0 mA, V_{CC} min(1)	TTL outputs	-	0.4	V
		CMOS outputs	-	0.4	V
V_{DR}	Data retention supply voltage (below which configuration data may be lost)		3.0	-	V
I_{CCO}	Quiescent FPGA supply current(2)	Commercial	-	3.0	mA
		Industrial	-	6.0	mA
I_L	Input or output leakage current		–10	+10	µA
C_{IN}	Input capacitance (sample tested)		-	10	pF
I_{RPU}	Pad pull-up (when selected) @ V_{IN} = 0V (sample tested)		0.02	0.25	mA
I_{RPD}	Pad pull-down (when selected) @ V_{IN} = 5V (sample tested)		0.02	-	mA

Notes:
1. With 50% of the outputs simultaneously sinking 12 mA, up to a maximum of 64 pins.
2. With no output current loads, no active input pull-up resistors, all package pins at V_{CC} or GND, and the FPGA configured with a Tie option.

Spartan Family Global Buffer Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

When fewer vertical clock lines are connected, the clock distribution is faster; when multiple clock lines per column are driven from the same global clock, the delay is longer. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade -4 Max	Speed Grade -3 Max	Units
T_{PG}	From pad through Primary buffer, to any clock K	XCS05	2.0	4.0	ns
		XCS10	2.4	4.3	ns
		XCS20	2.8	5.4	ns
		XCS30	3.2	5.8	ns
		XCS40	3.5	6.4	ns
T_{SG}	From pad through Secondary buffer, to any clock K	XCS05	2.5	4.4	ns
		XCS10	2.9	4.7	ns
		XCS20	3.3	5.8	ns
		XCS30	3.6	6.2	ns
		XCS40	3.9	6.7	ns

Spartan Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and are expressed in nanoseconds unless otherwise noted.

Symbol	Single Port RAM	Size(1)	Speed Grade -4 Min	-4 Max	-3 Min	-3 Max	Units
Write Operation							
T_{WCS}	Address write cycle time (clock K period)	16x2	8.0	-	11.6	-	ns
T_{WCTS}		32x1	8.0	-	11.6	-	ns
T_{WPS}	Clock K pulse width (active edge)	16x2	4.0	-	5.8	-	ns
T_{WPTS}		32x1	4.0	-	5.8	-	ns
T_{ASS}	Address setup time before clock K	16x2	1.5	-	2.0	-	ns
T_{ASTS}		32x1	1.5	-	2.0	-	ns
T_{AHS}	Address hold time after clock K	16x2	0.0	-	0.0	-	ns
T_{AHTS}		32x1	0.0	-	0.0	-	ns
T_{DSS}	DIN setup time before clock K	16x2	1.5	-	2.7	-	ns
T_{DSTS}		32x1	1.5	-	1.7	-	ns
T_{DHS}	DIN hold time after clock K	16x2	0.0	-	0.0	-	ns
T_{DHTS}		32x1	0.0	-	0.0	-	ns
T_{WSS}	WE setup time before clock K	16x2	1.5	-	1.6	-	ns
T_{WSTS}		32x1	1.5	-	1.6	-	ns
T_{WHS}	WE hold time after clock K	16x2	0.0	-	0.0	-	ns
T_{WHTS}		32x1	0.0	-	0.0	-	ns
T_{WOS}	Data valid after clock K	16x2	-	6.5	-	7.9	ns
T_{WOTS}		32x1	-	7.0	-	9.3	ns
Read Operation							
T_{RC}	Address read cycle time	16x2	2.6	-	2.6	-	ns
T_{RCT}		32x1	3.8	-	3.8	-	ns
T_{ILO}	Data valid after address change (no Write Enable)	16x2	-	1.2	-	1.6	ns
T_{IHO}		32x1	-	2.0	-	2.7	ns
T_{ICK}	Address setup time before clock K	16x2	1.8	-	2.4	-	ns
T_{IHCK}		32x1	2.9	-	3.9	-	ns

Notes:

1. Timing for 16 x 1 RAM option is identical to 16 x 2 RAM timing.

Spartan Family IOB Input Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade -4 Min	Speed Grade -4 Max	Speed Grade -3 Min	Speed Grade -3 Max	Units
Setup Times - TTL Inputs(1)							
T_{ECIK}	Clock Enable (EC) to Clock (IK), no delay	All devices	1.6	-	2.1	-	ns
T_{PICK}	Pad to Clock (IK), no delay	All devices	1.5	-	2.0	-	ns
Hold Times							
T_{IKEC}	Clock Enable (EC) to Clock (IK), no delay	All devices	0.0	-	0.9	-	ns
	All Other Hold Times	All devices	0.0	-	0.0	-	ns
Propagation Delays - TTL Inputs(1)							
T_{PID}	Pad to I1, I2	All devices	-	1.5	-	2.0	ns
T_{PLI}	Pad to I1, I2 via transparent input latch, no delay	All devices	-	2.8	-	3.6	ns
T_{IKRI}	Clock (IK) to I1, I2 (flip-flop)	All devices	-	2.7	-	2.8	ns
T_{IKLI}	Clock (IK) to I1, I2 (latch enable, active Low)	All devices	-	3.2	-	3.9	ns
Delay Adder for Input with Delay Option							
T_{Delay}	$T_{ECIKD} = T_{ECIK} + T_{Delay}$ $T_{PICKD} = T_{PICK} + T_{Delay}$ $T_{PDLI} = T_{PLI} + T_{Delay}$	XCS05	3.6	-	4.0	-	ns
		XCS10	3.7	-	4.1	-	ns
		XCS20	3.8	-	4.2	-	ns
		XCS30	4.5	-	5.0	-	ns
		XCS40	5.5	-	5.5	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	11.5	-	13.5	-	ns
T_{RRI}	Delay from GSR input to any Q	XCS05	-	9.0	-	11.3	ns
		XCS10	-	9.5	-	11.9	ns
		XCS20	-	10.0	-	12.5	ns
		XCS30	-	10.5	-	13.1	ns
		XCS40	-	11.0	-	13.8	ns

Notes:

1. Delay adder for CMOS Inputs option: for -3 speed grade, add 0.4 ns; for -4 speed grade, add 0.2 ns.
2. Input pad setup and hold times are specified with respect to the internal clock (IK). For setup and hold times with respect to the clock input, see the pin-to-pin parameters in the Pin-to-Pin Input Parameters table.
3. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Spartan Family IOB Output Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values are expressed in nanoseconds unless otherwise noted.

Symbol	Description	Device	Speed Grade				Units
			-4		-3		
			Min	Max	Min	Max	
Clocks							
T_{CH}	Clock High	All devices	3.0	-	4.0	-	ns
T_{CL}	Clock Low	All devices	3.0	-	4.0	-	ns
Propagation Delays - TTL Outputs(1,2)							
T_{OKPOF}	Clock (OK) to Pad, fast	All devices	-	3.3	-	4.5	ns
T_{OKPOS}	Clock (OK to Pad, slew-rate limited	All devices	-	6.9	-	7.0	ns
T_{OPF}	Output (O) to Pad, fast	All devices	-	3.6	-	4.8	ns
T_{OPS}	Output (O) to Pad, slew-rate limited	All devices	-	7.2	-	7.3	ns
T_{TSHZ}	3-state to Pad High-Z (slew-rate independent)	All devices	-	3.0	-	3.8	ns
T_{TSONF}	3-state to Pad active and valid, fast	All devices	-	6.0	-	7.3	ns
T_{TSONS}	3-state to Pad active and valid, slew-rate limited	All devices	-	9.6	-	9.8	ns
Setup and Hold Times							
T_{OOK}	Output (O) to clock (OK) setup time	All devices	2.5	-	3.8	-	ns
T_{OKO}	Output (O) to clock (OK) hold time	All devices	0.0	-	0.0	-	ns
T_{ECOK}	Clock Enable (EC) to clock (OK) setup time	All devices	2.0	-	2.7	-	ns
T_{OKEC}	Clock Enable (EC) to clock (OK) hold time	All devices	0.0	-	0.5	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	11.5		13.5		ns
T_{RPO}	Delay from GSR input to any Pad	XCS05	-	12.0	-	15.0	ns
		XCS10	-	12.5	-	15.7	ns
		XCS20	-	13.0	-	16.2	ns
		XCS30	-	13.5	-	16.9	ns
		XCS40	-	14.0	-	17.5	ns

Notes:

1. Delay adder for CMOS Outputs option (with fast slew rate option): for -3 speed grade, add 1.0 ns; for -4 speed grade, add 0.8 ns.
2. Delay adder for CMOS Outputs option (with slow slew rate option): for -3 speed grade, add 2.0 ns; for -4 speed grade, add 1.5 ns.
3. Output timing is measured at ~50% V_{CC} threshold, with 50 pF external capacitive loads including test fixture. Slew-rate limited output rise/fall times are approximately two times longer than fast output rise/fall times.
4. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Spartan-XL Family Global Buffer Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

When fewer vertical clock lines are connected, the clock distribution is faster; when multiple clock lines per column are driven from the same global clock, the delay is longer. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade -5 Max	Speed Grade -4 Max	Units
T_{GLS}	From pad through buffer, to any clock K	XCS05XL	1.4	1.5	ns
		XCS10XL	1.7	1.8	ns
		XCS20XL	2.0	2.1	ns
		XCS30XL	2.3	2.5	ns
		XCS40XL	2.6	2.8	ns

XCS05 and XCS05XL Device Pinouts

XCS05/XL Pad Name	PC84(4)	VQ100	Bndry Scan
I/O	P70	P71	238(3)
I/O (D0(2), DIN)	P71	P72	241(3)
I/O, SGCK4(1), GCK6(2) (DOUT)	P72	P73	244(3)
CCLK	P73	P74	-
VCC	P74	P75	-
O, TDO	P75	P76	0
GND	P76	P77	-
I/O	P77	P78	2
I/O, PGCK4(1), GCK7(2)	P78	P79	5
I/O (CS1(2))	P79	P80	8
I/O	P80	P81	11
I/O	P81	P82	14
I/O	P82	P83	17
I/O	-	P84	20
I/O	-	P85	23
I/O	P83	P86	26
I/O	P84	P87	29
GND	P1	P88	-

Notes:
1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The "PWRDWN" on the XCS05XL is not part of the Boundary Scan chain. For the XCS05XL, subtract 1 from all Boundary Scan numbers from GCK3 on (127 and higher).
4. PC84 package discontinued by PDN2004-01

XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84(4)	VQ100	CS144(2,4)	TQ144	Bndry Scan
VCC	P2	P89	D7	P128	-
I/O	P3	P90	A6	P129	44
I/O	P4	P91	B6	P130	47
I/O	-	P92	C6	P131	50
I/O	-	P93	D6	P132	53
I/O	P5	P94	A5	P133	56
I/O	P6	P95	B5	P134	59
I/O	-	-	C5	P135	62
I/O	-	-	D5	P136	65
GND	-	-	A4	P137	-
I/O	P7	P96	B4	P138	68
I/O	P8	P97	C4	P139	71
I/O	-	-	A3	P140	74
I/O	-	-	B3	P141	77
I/O	P9	P98	C3	P142	80

XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84(4)	VQ100	CS144(2,4)	TQ144	Bndry Scan
I/O, SGCK1(1) GCK8(2)	P10	P99	A2	P143	83
VCC	P11	P100	B2	P144	-
GND	P12	P1	A1	P1	-
I/O, PGCK1(1) GCK1(2)	P13	P2	B1	P2	86
I/O	P14	P3	C2	P3	89
I/O	-	-	C1	P4	92
I/O	-	-	D4	P5	95
I/O, TDI	P15	P4	D3	P6	98
I/O, TCK	P16	P5	D2	P7	101
GND	-	-	D1	P8	-
I/O	-	-	E4	P9	104
I/O	-	-	E3	P10	107
I/O, TMS	P17	P6	E2	P11	110
I/O	P18	P7	E1	P12	113
I/O	-	-	F4	P13	116
I/O	-	P8	F3	P14	119
I/O	P19	P9	F2	P15	122
I/O	P20	P10	F1	P16	125
GND	P21	P11	G2	P17	-
VCC	P22	P12	G1	P18	-
I/O	P23	P13	G3	P19	128
I/O	P24	P14	G4	P20	131
I/O	-	P15	H1	P21	134
I/O	-	-	H2	P22	137
I/O	P25	P16	H3	P23	140
I/O	P26	P17	H4	P24	143
I/O	-	-	J1	P25	146
I/O	-	-	J2	P26	149
GND	-	-	J3	P27	-
I/O	P27	P18	J4	P28	152
I/O	-	P19	K1	P29	155
I/O	-	-	K2	P30	158
I/O	-	-	K3	P31	161
I/O	P28	P20	L1	P32	164
I/O, SGCK2(1) GCK2(2)	P29	P21	L2	P33	167
Not Connected(1) M1(2)	P30	P22	L3	P34	170
GND	P31	P23	M1	P35	-
MODE(1), M0(2)	P32	P24	M2	P36	173

XCS30 and XCS30XL Device Pinouts *(Continued)*

XCS30/XL Pad Name	VQ100(5)	TQ144	PQ208	PQ240	BG256(5)	CS280(2,5)	Bndry Scan
I/O	P18	P28	P44	P52	V1	T1	272
I/O	P19	P29	P45	P53	T4	T2	275
I/O	-	P30	P46	P54	U3	T3	278
I/O	-	P31	P47	P55	V2	U1	281
I/O	P20	P32	P48	P56	W1	V1	284
I/O, SGCK2(1), GCK2(2)	P21	P33	P49	P57	V3	U2	287
Not Connected(1), M1(2)	P22	P34	P50	P58	W2	V2	290
GND	P23	P35	P51	P59	GND(4)	GND(4)	-
MODE(1), M0(2)	P24	P36	P52	P60	Y1	W1	293
VCC	P25	P37	P53	P61	VCC(4)	U3	-
Not Connected (1), $\overline{\text{PWRDWN}}$(2)	P26	P38	P54	P62	W3	V3	294 (1)
I/O, PGCK2(1), GCK3(2)	P27	P39	P55	P63	Y2	W2	295 (3)
I/O (HDC)	P28	P40	P56	P64	W4	W3	298 (3)
I/O	-	P41	P57	P65	V4	T4	301 (3)
I/O	-	P42	P58	P66	U5	U4	304 (3)
I/O	P29	P43	P59	P67	Y3	V4	307 (3)
I/O ($\overline{\text{LDC}}$)	P30	P44	P60	P68	Y4	W4	310 (3)
I/O	-	-	P61	P69	V5	T5	313 (3)
I/O	-	-	P62	P70	W5	W5	316 (3)
I/O	-	-	P63	P71	Y5	R6	319 (3)
I/O	-	-	P64	P72	V6	U6	322 (3)
I/O	-	-	P65	P73	W6	V6	325 (3)
I/O	-	-	-	P74	Y6	T6	328 (3)
GND	-	P45	P66	P75	GND(4)	GND(4)	-
I/O	-	P46	P67	P76	W7	W6	331 (3)
I/O	-	P47	P68	P77	Y7	U7	334 (3)
I/O	P31	P48	P69	P78	V8	V7	337 (3)
I/O	P32	P49	P70	P79	W8	W7	340 (3)
VCC	-	-	P71	P80	VCC(4)	T7	-
I/O	-	-	P72	P81	Y8	W8	343 (3)
I/O	-	-	P73	P82	U9	U8	346 (3)
I/O	-	-	-	P84	Y9	W9	349 (3)
I/O	-	-	-	P85	W10	V9	352 (3)
I/O	P33	P50	P74	P86	V10	U9	355 (3)
I/O	P34	P51	P75	P87	Y10	T9	358 (3)
I/O	P35	P52	P76	P88	Y11	W10	361 (3)
I/O ($\overline{\text{INIT}}$)	P36	P53	P77	P89	W11	V10	364 (3)
VCC	P37	P54	P78	P90	VCC(4)	U10	-
GND	P38	P55	P79	P91	GND(4)	GND(4)	-
I/O	P39	P56	P80	P92	V11	T10	367 (3)
I/O	P40	P57	P81	P93	U11	R10	370 (3)
I/O	P41	P58	P82	P94	Y12	W11	373 (3)
I/O	P42	P59	P83	P95	W12	V11	376 (3)
I/O	-	-	P84	P96	V12	U11	379 (3)

XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280(2,5)	Bndry Scan
O, TDO	P157	P181	A19	B17	0
GND	P158	P182	GND(4)	GND(4)	-
I/O	P159	P183	B18	A18	2
I/O, PGCK4(1), GCK7(2)	P160	P184	B17	A17	5
I/O	P161	P185	C17	D16	8
I/O	P162	P186	D16	C16	11
I/O (CS1(2))	P163	P187	A18	B16	14
I/O	P164	P188	A17	A16	17
I/O	-	-	-	E15	20
I/O	-	-	-	C15	23
I/O	P165	P189	C16	D15	26
I/O	-	P190	B16	A15	29
I/O	P166	P191	A16	E14	32
I/O	P167	P192	C15	C14	35
I/O	P168	P193	B15	B14	38
I/O	P169	P194	A15	D14	41
GND	P170	P196	GND(4)	GND(4)	-
I/O	P171	P197	B14	A14	44
I/O	P172	P198	A14	C13	47
I/O	-	P199	C13	B13	50
I/O	-	P200	B13	A13	53
VCC	P173	P201	VCC(4)	VCC(4)	-
I/O	-	-	A13	A12	56
I/O	-	-	D12	C12	59
I/O	P174	P202	C12	B12	62
I/O	P175	P203	B12	D12	65
I/O	P176	P205	A12	A11	68
I/O	P177	P206	B11	B11	71
I/O	P178	P207	C11	C11	74
I/O	P179	P208	A11	D11	77
I/O	P180	P209	A10	A10	80
I/O	P181	P210	B10	B10	83
GND	P182	P211	GND(4)	GND(4)	-

2/8/00

Notes:

1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The "PWRDWN" on the XCS40XL is not part of the Boundary Scan chain. For the XCS40XL, subtract 1 from all Boundary Scan numbers from GCK3 on (343 and higher).
4. Pads labeled GND(4) or V_{CC}(4) are internally bonded to Ground or V_{CC} planes within the package.
5. CS280 package discontinued by PDN2004-01

Additional XCS40/XL Package Pins

PQ240

GND Pins					
P22	P37	P83	P98	P143	P158
P204	P219	-	-	-	-
Not Connected Pins					
P195	-	-	-	-	-

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BG256

VCC Pins					
C14	D6	D7	D11	D14	D15
E20	F1	F4	F17	G4	G17
K4	L17	P4	P17	P19	R2
R4	R17	U6	U7	U10	U14
U15	V7	W20	-	-	-
GND Pins					
A1	B7	D4	D8	D13	D17
G20	H4	H17	N3	N4	N17
U4	U8	U13	U17	W14	-

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VCC Pins					
A1	A7	B5	B15	C10	C17
D13	E3	E18	G1	G19	K2
K17	M4	N16	R3	R18	T7
U3	U10	U17	V5	V15	W13
GND Pins					
E5	E7	E8	E9	E11	E12
E13	G5	G15	H5	H15	J5
J15	L5	L15	M5	M15	N5
N15	R7	R8	R9	R11	R12
R13	-	-	-	-	-

5/19/99

Revision History

The following table shows the revision history for this document.

Date	Version	Description
11/20/98	1.3	Added Spartan-XL specs and Power Down.
01/06/99	1.4	All Spartan-XL -4 specs designated Preliminary with no changes.
03/02/00	1.5	Added CS package, updated Spartan-XL specs to Final.
09/19/01	1.6	Reformatted, updated power specs, clarified configuration information. Removed T_{SOL} soldering information from Absolute Maximum Ratings table. Changed Figure 26: Slave Serial Mode Characteristics: T_{CCH}, T_{CCL} from 45 to 40 ns. Changed Master Mode Configuration Switching Characteristics: T_{CCLK} min. from 80 to 100 ns. Added Total Dist. RAM Bits to Table 1; added **Start-Up**, page 36 characteristics.
06/27/02	1.7	Clarified Express Mode pseudo daisy chain. Added new Industrial options. Clarified XCS30XL CS280 V_{CC} pinout.
06/26/08	1.8	Noted that PC84, CS144, and CS280 packages, and VQ100 and BG256 packages for XCS30 only, are discontinued by **PDN2004-01**. Extended description of recommended maximum delay of reconfiguration in **Delaying Configuration After Power-Up**, page 35. Added reference to Pb-free package options and provided link to **Package Specifications**, page 81. Updated links.
03/01/13	2.0	The products listed in this data sheet are obsolete. See **XCN10016** and **XCN11010** for further information.